

Monolithic N-Channel JFET Duals

Product Summary

Part Number	$V_{GS(off)}$ (V)	$V_{(BR)GSS}$ Min (V)	g_{fs} Min (mS)	I_G Typ (pA)	$ V_{GS1} - V_{GS2} $ Max (mV)
SST440	-1 to -6	-25	4.5	-1	10
SST441	-1 to -6	-25	4.5	-1	20

SST441, For applications information see AN102, page 6.

Features

- Monolithic Design
- High Slew Rate
- Low Offset/Drift Voltage
- Low Gate Leakage: 1 pA
- Low Noise
- High CMRR: 90 dB

Benefits

- Tight Differential Match vs. Current
- Improved Op Amp Speed, Settling Time Accuracy
- High-Speed Performance
- Minimum Input Error/Trimming Requirement
- Insignificant Signal Loss/Error Voltage
- High System Sensitivity
- Minimum Error with Large Input Signal

Applications

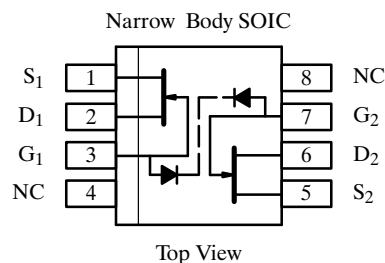
- Wideband Differential Amps
- High-Speed, Temp-Compensated, Single-Ended Input Amps
- High Speed Comparators
- Impedance Converters

Description

The SST440/441 are monolithic high-speed dual JFETs mounted in a single SO-8 package. These JFETs are an excellent choice for use as wideband differential amplifiers in demanding test and measurement applications.

The SO-8 package is available with tape-and-reel options to support automated assembly (see Packaging Information).

For similar products in TO-71 packaging, see the U440/441 data sheet.



Absolute Maximum Ratings

Gate-Drain, Gate-Source Voltage	-25 V
Gate Current	50 mA
Lead Temperature ($1/16''$ from case for 10 sec.)	300°C
Storage Temperature	-55 to 150°C
Operating Junction Temperature	-55 to 150°C

Power Dissipation :	Per Side ^a	300 mW
	Total ^b	500 mW

Notes

- Derate 2.4 mW/°C above 25°C
- Derate 4 mW/°C above 25°C

Specifications^a

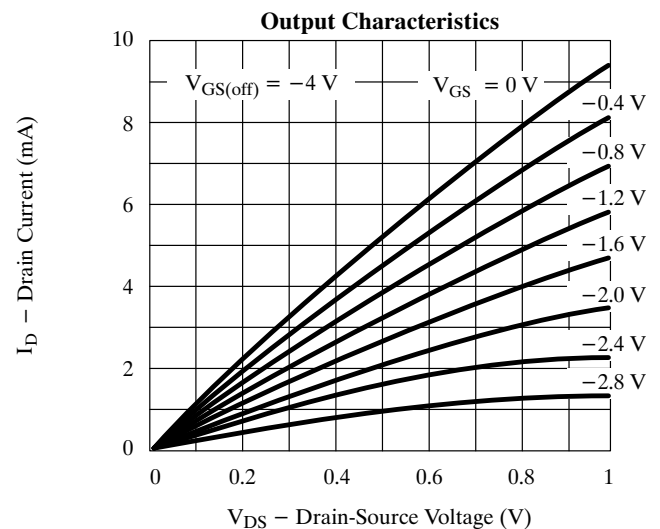
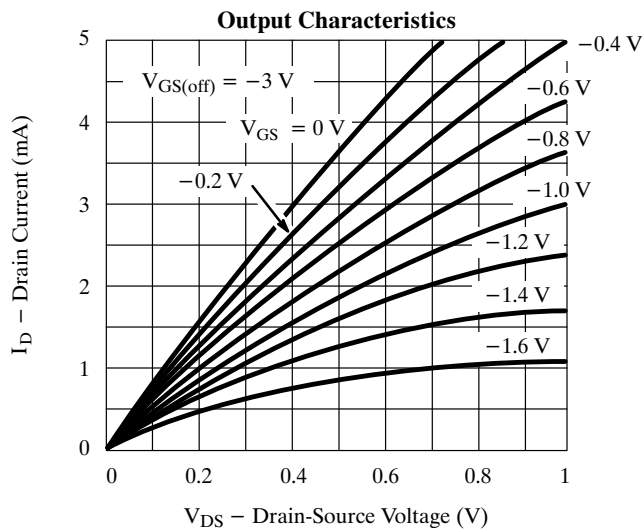
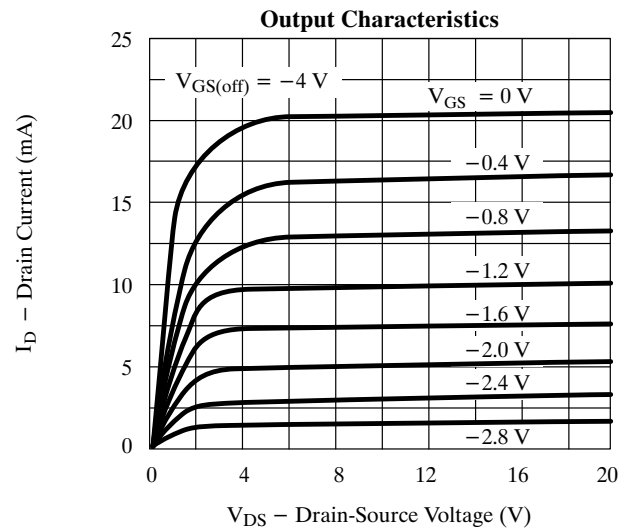
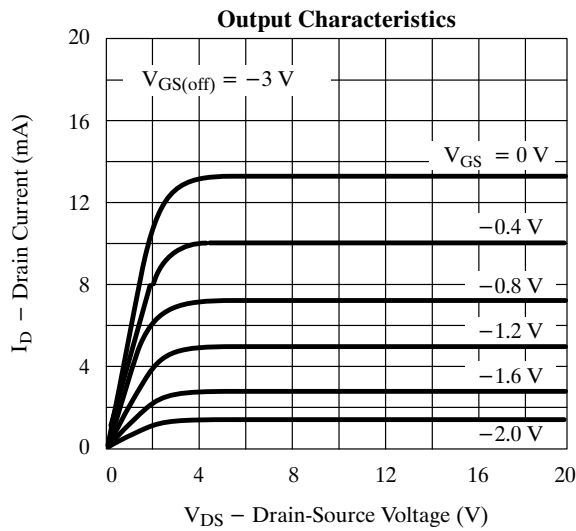
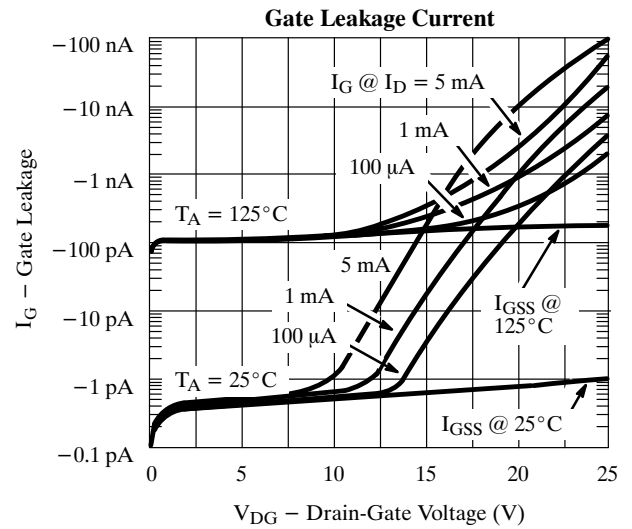
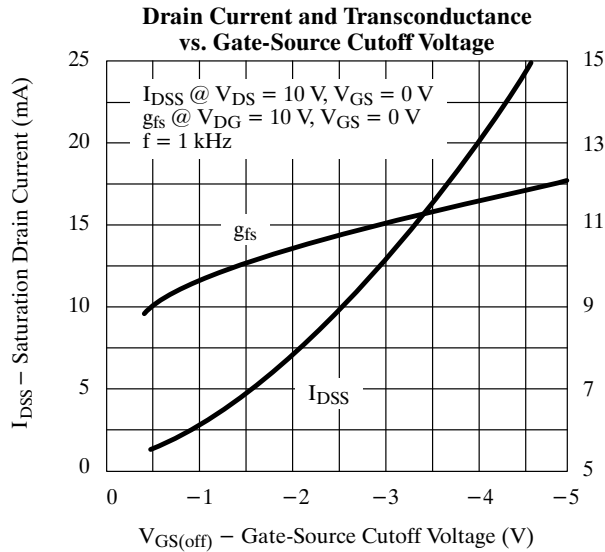
Parameter	Symbol	Test Conditions	Typ ^b	Limits				Unit
				SST440		SST441		
				Min	Max	Min	Max	
Static								
Gate-Source Breakdown Voltage	$V_{(BR)GSS}$	$I_G = -1 \mu A, V_{DS} = 0 V$	-35	-25		-25		V
Gate-Source Cutoff Voltage	$V_{GS(off)}$	$V_{DS} = 10 V, I_D = 1 nA$	-3.5	-1	-6	-1	-6	
Saturation Drain Current ^c	I_{DSS}	$V_{DS} = 10 V, V_{GS} = 0 V$	15	6	30	6	30	mA
Gate Reverse Current	I_{GSS}	$V_{GS} = -15 V, V_{DS} = 0 V$	-1		-500		-500	pA
		$T_A = 125^\circ C$	-0.2					nA
Gate Operating Current	I_G	$V_{DG} = 10 V, I_D = 5 mA$	-1		-500		-500	pA
		$T_A = 125^\circ C$	-0.2					nA
Gate-Source Forward Voltage	$V_{GS(F)}$	$I_G = 1 mA, V_{DS} = 0 V$	0.7					V
Dynamic								
Common-Source Forward Transconductance	g_{fs}	$V_{DS} = 10 V, I_D = 5 mA$ $f = 1 kHz$	6	4.5	9	4.5	9	mS
Common-Source Output Conductance	g_{os}		20		200		200	μS
Common-Source Forward Transconductance	g_{fs}	$V_{DS} = 10 V, I_D = 5 mA$ $f = 100 MHz$	5.5					mS
Common-Source Output Conductance	g_{os}		30					μS
Common-Source Input Capacitance	C_{iss}	$V_{DS} = 10 V, I_D = 5 mA$ $f = 1 MHz$	3.5					pF
Common-Source Reverse Transfer Capacitance	C_{rss}		1					
Equivalent Input Noise Voltage	\bar{e}_n	$V_{DS} = 10 V, I_D = 5 mA$ $f = 10 kHz$	4					nV/\sqrt{Hz}
Matching								
Differential Gate-Source Voltage	$ V_{GS1} - V_{GS2} $	$V_{DG} = 10 V, I_D = 5 mA$	7		10		20	mV
Gate-Source Voltage Differential Change with Temperature	$\frac{\Delta V_{GS1} - V_{GS2} }{\Delta T}$	$V_{DG} = 10 V, I_D = 5 mA$ $T_A = -55 to 125^\circ C$	10					$\mu V/^\circ C$
Saturation Drain Current Ratio ^d	$\frac{I_{DSS1}}{I_{DSS2}}$	$V_{DS} = 10 V, V_{GS} = 0 V$	0.98					
Transconductance Ratio ^d	$\frac{g_{fs1}}{g_{fs2}}$	$V_{DS} = 10 V, I_D = 5 mA$ $f = 1 kHz$	0.98					
Common Mode Rejection Ratio	CMRR	$V_{DG} = 10 to 15 V, I_D = 5 mA$	90					dB

Notes

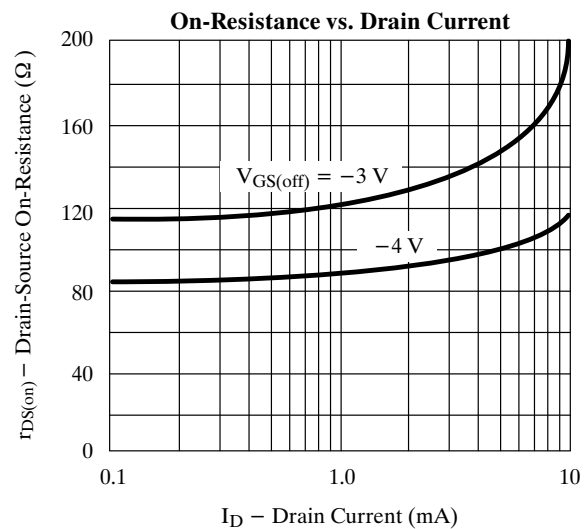
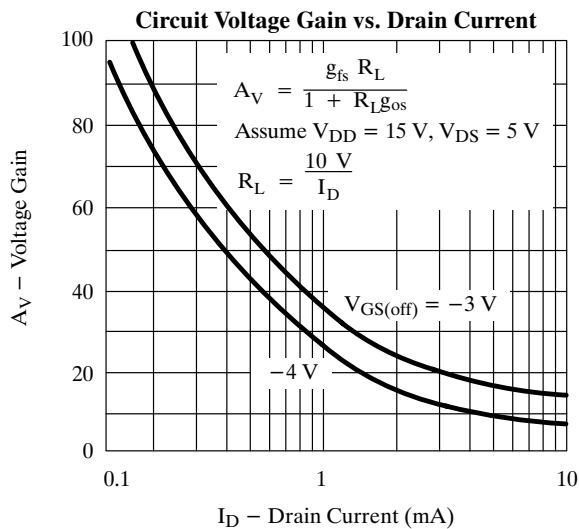
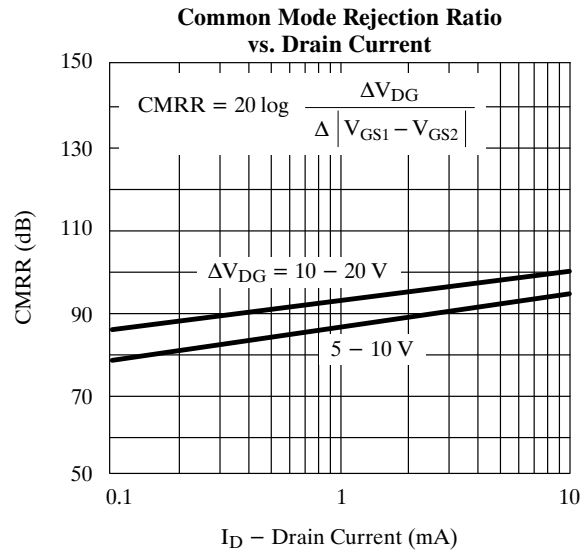
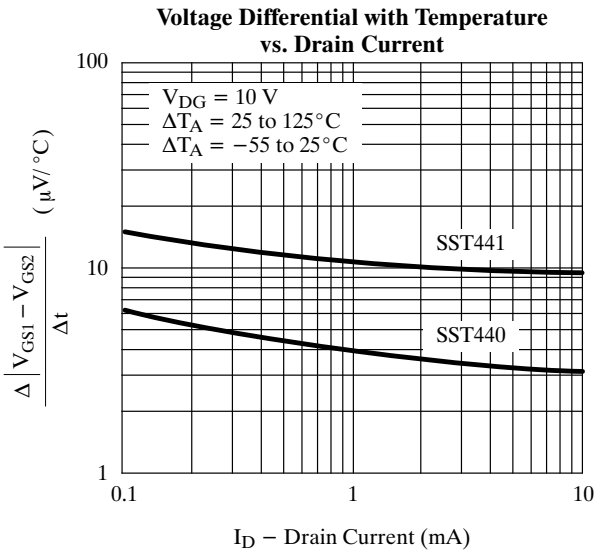
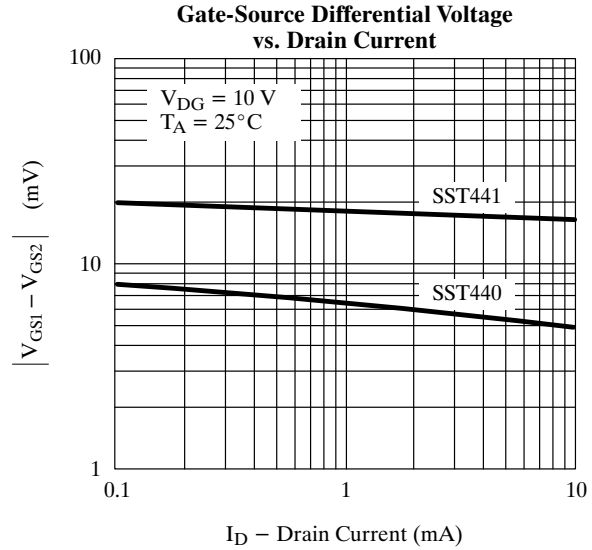
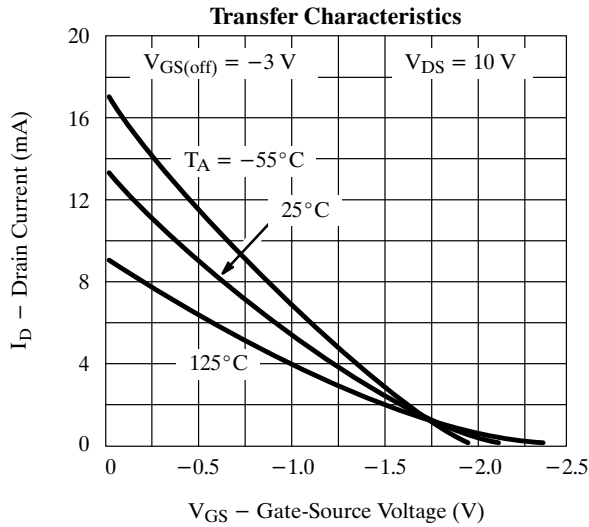
- $T_A = 25^\circ C$ unless otherwise noted.
- Typical values are for DESIGN AID ONLY, not guaranteed nor subject to production testing.
- Pulse test: $PW \leq 300 \mu s$ duty cycle $\leq 3\%$.
- Assumes smaller value in the numerator.

NNZ

Typical Characteristics



Typical Characteristics (Cont'd)



Typical Characteristics (Cont'd)

